

PATENT

**IN THE UNITED STATES PATENT AND
TRADEMARK OFFICE**

Inventor: Buxton, et al. Docket No.: TAI.0800
Serial No.: 10/730,388 Examiner: Khuu, Cindy D.
Filing Date: December 07, 2003 Art Unit: 2863
Title: Methods and Apparatus for Data Analysis

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner of Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Commissioner:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and pursuant to 37 C.F.R. §§1.97-1.98, the reference or references listed and identified on the attached PTO/SB/08-based form are being submitted for consideration by the Examiner.

The applicant further provides the following information for which no written references are possessed:

- The article: Variance Reduction Using Wafer Patterns, Daasch, McNames, Bockelman, Cota (2003);
- The company LSI may have a commercial SPP solution using Nearest-Neighbor Residual (NNR) technology that may be relevant; and
- Mr. Charles Meyerson of Medtronic may have information about LSI's NNR/SPP techniques that may be relevant.

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The preceding information and the attached references are cited only in the interest of candor and without any admission that they constitute statutory prior art or contain matter which anticipates the invention or which would render the same obvious, either singly or in combination, to a person of ordinary skill in the art.

This Information Disclosure Statement (IDS) is being filed under 37 C.F.R. §1.97(c) before the mailing date of any final action under 37 C.F.R. §1.113, a notice of allowance under 37 C.F.R. §1.311, or an action that otherwise closes prosecution of the application. The IDS is accompanied by the fee set forth in 37 C.F.R. §1.17(p). If there are any questions concerning this IDS, the Examiner is requested to contact the undersigned.

Respectfully submitted,

Date: 22 DEC 06

By: 
Daniel J. Noblitt
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				Application Number	10/730,388
				Filing Date	December 07, 2003
				First Named Inventor	Buxton
				Art Unit	2863
				Examiner Name	KHUU, CINDY
Sheet	1	of	8	Attorney Docket Number	TAI.0800

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		T ²
		APPLEWHITE. The view from the top. IEEE Spectrum, 41(II (INT)):18–31, Nov 2004.		
		Canuto, M. Fairhurst and G. Howells, (2001) Improving ARTMap learning through variable vigilance. International Journal of Neural Systems, Vol. 11, No. 6, pp. 509-522.		
		Carpenter, G. A. and S. Grossberg, (1998) The ART of adaptive pattern recognition by self-organization neural network. Computer, vol. 21, no. 3, pp. 77-88.		
		K. Chang and J. Ghosh. Principal Curve Classifier – A nonlinear approach to pattern classification. In IEEE World Congress on Computational Intelligence, Neural... May1998		
		M. Clerc and J. Kennedy. The particle swarm - explosion, stability, and convergence in a multidimensional complex space. IEEE Transaction on Evolutionary Computation, Feb 2002		
		R. C. Eberhart and J. Kennedy, "A new optimizer using particle swarm theory", in Proc. 6th Intl. Symposium on Micro Machines and Human Science, Nagoya, Japan, IEEE 1995		
		R. C. Eberhart and Y. Shi. Evolving Artificial Neural Networks. In International Conference on Neural Networks and Brain, pages PL5 – PL13, Beijing, P.R. China, 1998		
		R. C. Eberhart and X. Hu, "Human Tremor analysis using particle swarm optimization", in Proc. Congress on Evolutionary Computation 1999, IEEE Service Center, pp 1927-1930		
		R.C. Eberhart and Y. Shi, "Comparing inertia weight and constriction factors in particle swarm optimization", in Proc. of the Congress of Evolutionary Computation, 2000		
		F. Chen and S. Liu, "A Neural-Network Approach To Recognize Defect Spatial Pattern In Semiconductor Fabrication", IEEE Transactions on Semiconductor Manufacturing,v.13 2000		

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		T. Fountain, T. Dietterich, and B. Sudyka. Mining IC test data to optimize VLSI testing. the 6th ACM SIGKDD International Conference pages 18–25, 2000	
		N. Franken and A.P. Engelbrecht. Comparing PSO structures to learn the game of checkers from zero knowledge. In Congress on Evolutionary Computation, volume 1, Dec 2003	
		F. van den Bergh and A. P. Engelbrecht, "Cooperative Learning In Neural Networks using Particle Swarm Optimizers", South African Computer Journal, pp. 84–90, Nov. 2000	
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		S.S. Gleason, K.W. Tobin, T.P. Karnowski, and Fred Lakhani, (1999) Rapid Yield Learning through Optical Defect and Electrical Test Analysis, SPIE, 1999	
		Hu M. K. "Visual pattern recognition by moments invariants", IRE Transactions on Information Theory, Vol. 8(2), pp. 179-187, 1962	
		The National Technology Roadmap for Semiconductors, Semiconductor Industry Association, San Jose, 2001 (Executive Summary)	
		The National Technology Roadmap for Semiconductors, Semiconductor Industry Association, San Jose, 2001 (Test and Test Equipment)	
		K. Kameyama, and Y. Kosugi, "Semiconductor Defect Classification using Hyperellipsoid Clustering Neural Networks and Model Switching", Int'l Joint Conf on Neural Networks 1999	

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		T.P. Kamowski, K.W. Tobin, S.S. Gleason, Fred Lakhani, "The Application of Spatial Signature Analysis to Electrical Test Data: Validation Study," SPIE 24th Ann'l Symp Feb1999	
		J. Kennedy and R. Mendes. Population structure and particle swarm performance. In Congress on Evolutionary Computation, pages 1671-1676, 2002.	
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		Leonardis and H. Bischof, "An efficient MDL-based construction of RBF networks", Neural Networks, vol. 11, pp963-973, 1998	
		Y. Liu, X. Yao and T. Higuchi, "Evolutionary Ensembles with Negative Correlation Learning", in IEEE Transactions on Evolutionary Computation, 4(4): 380-387, Nov. 2000	
		R. Mendes, J. Kennedy, and J. Neves. Watch thy neighbor or how the swarm can learn from its environment. IEEE Swarm Intelligence Symposium, pages 88 - 94, April 24-26 2003	
		R. Mendes, J. Kennedy, and J. Neves. The Fully Informed Particle: Simpler, Maybe Better. IEEE Transaction on Evolutionary Computation, 8:204-210, June 2004	

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		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003	
		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003 (PRESENTATION)	
		MIGUELANEZ, EMILIO, Automating the Analysis of Wafer Data Using Adaptive Resonance Theory Networks, 2004 (PRESENTATION)	
		MIGUELANEZ, EMILIO, Evolving Neural Networks using Swarm Intelligence for Binmap Classification, 2004	
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		MIGUELANEZ, EMILIO, Swarm Intelligence in Automated Electrical Wafer Sort Classification, 2005	
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		Neblett. The role of test in total quality management. In Proceedings of the IEEE Systems Readiness Technology Conference AUTOTESTCON'94, volume I, pages 727-735, sep 1994	
		Ozcan and C.K. Mohan. Particle swarm optimization: Surfing the waves. In International Congress on Evolutionary Computation, pages 1939-1944, 1999	

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		K. E. Parsopoulos and M. N. Vrahatis. On the Computation of All Global Minimizers through Particle Swarm Optimization. IEEE Transaction on Evolutionary Computation, June 2004	
		T. Poggio and F. Girosi, "Networks for approximation and learning", Proc. of the IEEE, vol. 78, pp1481-197, 1990	
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		Y. Shi and R.C. Eberhart, "Parameter selection in particle swarm optimization", In Proc. of the 1998 Annual Conference on Evolutionary Programming, San Diego, CA, 1998	
		Y. Shi and R. C. Eberhart. "A Modified Particle Swarm Optimizer", in Proc. of Intl. Joint Conf. on Neural Networks, Washington, USA, pp. 69-73, July 1999	
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		K.W. Tobin, S.S. Gleason, F. Lakhani, and M.H. Bennet, "Automated Analysis for Rapid Defect Sourcing and Yield Learning", Future Fab International, Vol. 4, 1997	
		K.W. Tobin, S. S. Gleason, T.P. Karnowski, and S.L. Cohen, Feature Analysis and classification of Manufacturing Signatures on Semiconductor Wafers. SPIE 9th Annual, 1997	
		K. W. Tobin, S. S. Gleason, T. P. Karnowski, S. L. Cohen and F. Lakhani, Automatic Classification of Spatial Signatures on Semiconductor Wafermaps, SPIE 22nd Annual, 1997	
		Tseng, L. Y. and Yang, S. B., "Genetic Algorithms for Clustering, Feature Selection and Classification", International Conference on Neural Networks, 9-12 June 1997	

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		Vafaie, H. and De Jong, K., "Genetic Algorithms as a Tool for Feature Selection in Machine Learning", 4th Int'l Conf on Tools with Artificial Intelligence, Nov. 1992	
		Watkins and L. Boggess. A new classifier based on resource limited Artificial Immune Systems. In Congress on Evolutionary Computation CEC'02, vol II, pp 1546-51. IEEE May 2002	
		C. Zhang, H. Shao, and Y. Li, "Particle swarm optimization for evolving artificial neural networks", IEEE Int'l Conf on Systems, Man and Cybernetics vol. 4, 2000	

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